

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re application of: Inderjit Singh et al.

Application No.: 10/633,004

Group No.: 2811

Filed: 07/31/2003

Examiner: Vu, Hung K.

For: PAD OVER ACTIVE CIRCUIT SYSTEM AND METHOD WITH MESHED SUPPORT
STRUCTURE

Mail Stop Petition

Commissioner for Patents

P.O. Box 1450

Alexandria, VA 22313-1450

PETITION TO WITHDRAW HOLDING OF ABANDONMENT

1. I hereby petition to withdraw the holding of abandonment in this case, on the basis that time period for taking subsequent action in connection with the Decision on Appeal mailed 03/27/2008 has not expired.
2. I hereby state:
 - (a) The Decision on Appeal was mailed 03/27/2008.
 - (b) The Notice of Abandonment was mailed on 04/10/2008.
 - (c) According to the following portions of the Manual of Patent Examining Procedure, Applicant is allowed to file a Request for Continued Examination up to two months after the Decision on Appeal:

1214.07 Reopening of Prosecution [R-3] - 1200 Appeal

Sometimes an amendment is filed after the Board's decision which does not carry into effect any recommendation made by the Board and which presents a new or amended claim or claims. In view of the fact that * prosecution is closed, the appellant is not entitled to have such amendment entered as a matter of right. However, if the amendment is submitted with a request for continued examination (RCE) under 37 CFR 1.114 and the fee set forth in 37 CFR 1.17(e), * prosecution of the application will be reopened and the amendment will be entered. See MPEP § 706.07(h), paragraph XI.

§ 1.114 Request for continued examination.

- (a) If prosecution in an application is closed, an applicant may request continued examination of the application by filing a submission and the fee set forth in § 1.17(e) prior to the earliest of:
- (1) Payment of the issue fee, unless a petition under § 1.313 is granted;
 - (2) Abandonment of the application; or
 - (3) The filing of a notice of appeal to the U.S. Court of Appeals for the Federal Circuit under 35 U.S.C. 141, or the commencement of a civil action under 35 U.S.C. 145 or 146, unless the appeal or civil action is terminated.

1214.06 Examiner Sustained in Whole or in Part [R-3] - 1200 Appeal

The time for seeking review of a decision of the Board by the Court of Appeals for the Federal Circuit or the U.S. District Court for the District of Columbia is the same for both tribunals, that is, 2 months, or 2 months with the extension provided by 37 CFR 1.304 in the event a request for rehearing is timely filed before the Board, or as extended by the *>Director<. See MPEP § 1216.

I. NO CLAIMS STAND ALLOWED

The proceedings in an application or *ex parte* reexamination proceeding are terminated as of the date of the expiration of the time for filing court action. The application is no longer considered as pending. It is to be stamped abandoned and sent to abandoned files.

3. I attach a copy of the Decision on Appeal mailed 03/27/2008 and the Notice of Abandonment mailed 04/10/2008.
4. In consideration of these submissions, it is respectfully requested that the holding of abandonment be withdrawn.
5. Applicants believe that no fees are due in connection with the filing of this paper because it is our belief that the Notice of Abandonment was issued in error. However, the Commissioner is authorized to charge any additional fees that may be due (e.g. for any reason including, but not limited to, fee changes, etc.) to Deposit Account No. 50-1351 (Order No.NVIDP234).

Date: May 27, 2008

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APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.
10/633,004	07/31/2003	Inderjit Singh	NVIDP234/P000825	8949
28875	7590	03/27/2008	EXAMINER	
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Please find below and/or attached an Office communication concerning this application or proceeding.

The time period for reply, if any, is set in the attached communication.

UNITED STATES PATENT AND TRADEMARK OFFICE

BEFORE THE BOARD OF PATENT APPEALS
AND INTERFERENCES

Ex parte INDERJIT SINGH, HOWARD LEE MARKS,
and JOSEPH DAVID GRECO

Appeal 2007-4511
Application 10/633,004
Technology Center 2800

Decided: March 26, 2008

Before ANITA PELLMAN GROSS, MAHSHID D. SAADAT,
and KEVIN F. TURNER, *Administrative Patent Judges*.

SAADAT, *Administrative Patent Judge*.

DECISION ON APPEAL

STATEMENT OF THE CASE

Appellants appeal under 35 U.S.C. § 134(a) from a final rejection of claims 1, 2, 4-18, 20, 21, 27, 29, and 30 which are all of the claims pending in this application as claims 3, 19, 22-26, 28, and 31 have been canceled.

We have jurisdiction under 35 U.S.C. § 6(b).

Appellants' invention relates to placement of metal layers and a bond pad, at least partially, above the active circuits in an integrated circuit (Spec. 3).

Claim 1 is representative of the claims on appeal and reads as follows:

1. An integrated circuit, comprising:

an active circuit;

a metal layer disposed, at least partially, above the active circuit; and

a bond pad disposed, at least partially, above the metal layer;

wherein the metal layer is meshed;

wherein the metal layer is disposed, at least partially, directly above the active circuit;

wherein the mesh ensures that bonds are capable of being placed over the active circuit without damage thereto during a bonding process;

wherein the active circuit includes a plurality of transistors, and an entirety of at least one of the transistors is disposed directly below the bond pad, and the mesh ensures that at least one of the bonds is capable of being placed over the at least one transistor without damage thereto during the bonding process.

The prior art relied upon by the Examiner in rejecting the claims on appeal is:

Tanaka	US 6,100,589	Aug. 8, 2000
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Suzuki	US 6,707,156 B2	Mar. 16, 2004 (filed Jan. 28, 2003)
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Appellants' Admitted Prior Art (AAPA), as depicted in Figures 1-2.

Claims 1, 2, 4-18, 20, 21, 27, 29, and 30 stand rejected under the first paragraph of 35 U.S.C. § 112 as containing subject matter which was not described in the Specification in such a way as to reasonably convey to one skilled in the relevant art that the inventor, at the time the application was filed, had possession of the claimed invention.

Claims 1, 4-18, 20, 27, 29, and 30 stand rejected under 35 U.S.C. § 103(a) based upon the teachings of Suzuki and Tanaka.

Claims 2 and 21 stand rejected under 35 U.S.C. § 103(a) based upon the teachings of Suzuki and Tanaka in view of AAPA.

Rather than reiterate the opposing arguments, reference is made to the Briefs and the Answer for the respective positions of Appellants and the Examiner. Only those arguments actually made by Appellants have been considered in this decision. Arguments which Appellants could have made but did not make in the Briefs have not been considered and are deemed to be waived. *See* 37 C.F.R. § 41.37(c)(1)(vii).

We affirm.

ISSUES

The first issue on appeal turns on whether under the first paragraph of 35 U.S.C. § 112, with respect to all the appealed claims, the Specification, as originally filed, supports the claimed “an entirety of at least one of the transistors is disposed directly below the bond pad.”

The second issue is whether under 35 U.S.C. § 103, with respect to appealed claims 1, 4-18, 20, 27, 29, and 30, the combination of Suzuki and Tanaka, as proposed by the Examiner, teaches or suggests the claimed subject matter.

The third issue is whether under 35 U.S.C § 103(a), with respect to appealed claims 2 and 21, one of ordinary skill in the art at the time of the invention would have found it obvious to modify Suzuki and Tanaka based on AAPA to render the claimed invention unpatentable.

PRINCIPLES OF LAW

Written Description

“The purpose of the written description requirement is to prevent an applicant from later asserting that he invented that which he did not; the applicant for a patent is therefore required ‘to recount his invention in such detail that his future claims can be determined to be encompassed within his original creation.’” *Amgen Inc. v. Hoechst Marion Roussel Inc.*, 314 F.3d 1313, 1330 (Fed. Cir. 2003) (citing *Vas-Cath Inc. v. Mahurkar*, 935 F.2d 1555, 1561 (Fed. Cir. 1991)). While there is no requirement that the claimed invention be described in the identical wording that was used in the Specification, there must be sufficient disclosure to show one of skill in this art that the inventor “invented what is claimed.” *See Union Oil Co. of California v. Atlantic Richfield Co.*, 208 F.3d 989, 997 (Fed. Cir. 2000) (citing *In re Gosteli*, 872 F.2d 1008, 1012 (Fed. Cir. 1989)).

The written description must be of sufficient detail to show possession of the full scope of the invention. *Pandrol USA LP v. Airboss Railway Products Inc.*, 424 F.3d 1161, 1165 (Fed. Cir. 2005).

Obviousness

In rejecting claims under 35 U.S.C. § 103, it is incumbent upon the Examiner to establish a factual basis to support the legal conclusion of obviousness. *See In re Fine*, 837 F.2d 1071, 1073 (Fed. Cir. 1988). In so

doing, the Examiner must make the factual determinations set forth in *Graham v. John Deere Co.*, 383 U.S. 1, 17 (1966). “[T]he examiner bears the initial burden, on review of the prior art or on any other ground, of presenting a *prima facie* case of unpatentability.” *In re Oetiker*, 977 F.2d 1443, 1445 (Fed. Cir. 1992).

In identifying a reason that would have prompted a person of ordinary skill in the relevant field to combine the prior art teachings, the Examiner must show some articulated reasoning with some rational underpinning to support the legal conclusion of obviousness. *KSR Int’l. v. Teleflex Inc.*, 127 S. Ct. 1727, 1741 (2007). “[T]here must be some articulated reasoning with some rational underpinning to support the legal conclusion of obviousness.” *In re Kahn*, 441 F.3d 977, 988 (Fed. Cir. 2006) (citing *In re Lee*, 277 F.3d 1338, 1343-46 (Fed. Cir. 2002); *In re Rouffet*, 149 F.3d 1350, 1355-59 (Fed. Cir. 1998)).

Further, a rejection based on section 103 must rest upon a factual basis rather than conjecture, or speculation. “Where the legal conclusion [of obviousness] is not supported by the facts it cannot stand.” *In re Warner*, 379 F.2d 1011, 1017 (CCPA 1967). *See also In re Kahn*, 441 F.3d at 988 (Fed. Cir. 2006).

ANALYSIS

35 U.S.C. § 112 Rejection of the claims

With respect to the written description issue, the Examiner asserts that disposing an entirety of at least one of the transistors directly below the bond pad, as recited in independent claims 1, 20, and 21, has no support in the originally filed Specification (Ans. 3). The Examiner acknowledges that Appellants’ disclosure specifies that the bond pad 306 is disposed above the

core 302 and/or above any part of the active circuit 308, while the active circuit 308 may include a plurality of transistors (Ans. 9-10). However, the Examiner argues that the disclosed placement of the bond pad 306 does not necessarily place an entirety of at least one of the transistors directly below the bond pad (Ans. 10).

Appellants contend that by virtue of the disclosure in the originally filed application, in pages 3 and 7 and the original claim 21, and since the active circuit and the core may include a plurality of transistors, while the bond pads may be disposed above the core and other parts of the active circuit, the disclosure meets the written description requirement (App. Br. 11). Appellants conclude that since the bond pads 306 may be disposed above the core 302 and any other part of the active circuit 308, and the core 302 of the active circuit 308 includes a plurality of transistors, the Specification does disclose “an entirety of at least one of the transistors is disposed directly below the bond pad,” as claimed (Reply Br. 3).

Upon a review of the arguments and the evidence of record, we find Appellants’ arguments to be persuasive. The original disclosure remains uncontested as having recited the bond pads being disposed above the core, and/or any other part of the active circuit (Spec. 7:15-17). Such an arrangement clearly indicates the placement of the bond pads over any part of the active circuit which includes both the core and the peripheral I/O bus or any devices formed in the integrated circuit. As argued by Appellants (Reply Br. 3), even if the exact wording is not used to explicitly disclose the disputed claim limitation, there is sufficient disclosure that shows one of ordinary skill in the art that Appellants invented and disclosed the specific claimed placement of the bond pads.

Thus, contrary to the Examiner's assertion, upon reading Appellants' disclosure, a person of ordinary skill in the art would be led to the conclusion that an entirety of at least one of the transistors would be able to be disposed directly below the bond pad, according to the claimed invention.

As there is sufficient disclosure in Appellants' Specification with respect to the placement of the bond pads, we find that the specified placement of the bond pads above the core and any other part of the active circuit represents a disclosed feature within the scope of the claimed and disclosed invention that represents no new matter. Accordingly, we do not sustain the rejection of claims 1, 2, 4-18, 20, 21, 27, 29, and 30 under 35 U.S.C. § 112, first paragraph, as containing subject matter which was not described in the Specification in such a way as to reasonably convey to one skilled in the relevant art that the inventor, at the time the application was filed, had possession of the claimed invention.

35 U.S.C. § 103 Rejection of Claims 1, 4-16, 20, 27, 29, and 30

Appellants contend that Tanaka and Suzuki address different problems of arranging bond pads and cannot be combined since Suzuki does not even mention bonding or any problems associated with the bonding-related damages to the active circuit (App. Br. 12; Reply Br. 5). The Examiner responds by relying on Figure 1 of Suzuki and stating that the bond pad is shown over a stack of metal layers and disposed above an entirety of at least one transistor (Ans. 10). The Examiner further points out that the bond pad disclosed in Suzuki must certainly be used for connection to a bond wire (*id.*).

We agree with the Examiner's assessment of the structure depicted in Figure 1 of Suzuki where active region 13 and its neighboring regions

correspond to an entirety of at least one transistor that is disposed directly below the bond pad, as represented by metal layer M11L. Suzuki further discloses that the metal layer M11L is a wiring layer or a pad (col. 4, ll. 58-67). Therefore, Suzuki discloses a bond pad, which is used for connection to the wiring, to be positioned over an entirety of at least a transistor in the active circuit area.

With respect to the recognition of any problems associated with bonding to the pad, we also agree with the Examiner that Suzuki describes how the dielectric layers between the metal layers are formed to reduce the stress induced by the stack (col. 6, ll. 16-31). Therefore, one of ordinary skill in the art would have concluded that some kind of stress is induced in the layers below the bond pad even before any bonding is performed.

Turning now to Tanaka, we note that Appellants take a similar position that the reference does not address the problem of bonding-related damage to the active circuit (App. Br. 12; Reply Br. 5-7). The Examiner argues that Tanaka does address the stress problem in the dielectric layers by forming the meshed metal layers in order to prevent formation of cracks in the insulating interlayers in the event force, such as that used for bonding, is applied to the bond pads (Ans. 10-11).

We also agree with the Examiner's analysis of Tanaka in suggesting the use of meshed metal layers to reduce stress. Tanaka specifically illustrates in Figure 21A and 21B the formation of stress-induced cracks in the dielectric layers between metal layers and how using meshed metal configuration strengthens the dielectric to resist cracking (col. 8, ll. 3-15).

We also remain unconvinced by Appellants' argument (Reply Br. 7) that Tanaka prevents cracks in the dielectric layer by using a prop of the

insulating interlayer film. Appellants appear to have taken the “prop” 130 shown in Figure 21B to be separate and different from the dielectric interlayer. Tanaka actually discloses that by using a meshed metal layer, the dielectric layer is formed in a continuous form through the opening in the mesh and connecting the two dielectric layers 150 and 160 (col. 8, ll. 5-8). Therefore, the solid portion 130 connecting the dielectric layers forms a much stronger block to support the metal layers even if force is applied during wire-bonding (col. 7, ll. 52-54). It is this solid area of continuous dielectric mass that Tanaka calls “prop,” whereas there is no other material other than the interlayer dielectric material.

We further agree with the Examiner’s rationale for combining Tanaka with Suzuki to further improve the reliability of the dielectric interlayers formed between the metal layer stack disclosed in Suzuki. Contrary to Appellants’ assertion related to the use of a gradual change in the dielectric constant in Suzuki (Reply Br. 8), as discussed above, one of ordinary skill in the art knowing about Tanaka would have used meshed metal layers in the structure of Suzuki to further reduce stress on the layers of dielectric as well as any other layer or active device that is disposed under the metal layer stack. Therefore, contrary to Appellants’ arguments (Appl. Br. 13), no matter how else Suzuki improves the stress problem in the dielectric layers, using the *KSR* standard, applying the teachings of Tanaka would have produced only predictable results and improved the device of Suzuki by protecting the lower layers from stress, both from dielectric layers having different constants and the pressure applied during wire-bonding to the bond pad of Suzuki.

Thus, based on our analysis above, we find that one of ordinary skill in the art would have found the Examiner's reliance on the combination of Suzuki and Tanaka to be reasonable in rendering the subject matter of claim 1 obvious. Therefore, to the extent claimed, the combination of Suzuki and Tanaka suggests the subject matter recited in claims 1, as well as claims 4-16, 20, 27, 29, and 30, argued together as one group with claim 1 (App. Br. 11).

35 U.S.C. § 103 Rejection of Claims 17 and 18

With respect to claim 17, Appellants argue that the vias shown in Figure 6A, as asserted by the Examiner, are not arranged in "at least two spaced rows" (App. Br. 15; Reply Br. 12-13). Appellants specifically refer to the limitations in the base claim and the intervening claims to argue that the claimed arrangement of vias in the first portions is not shown in Tanaka (*id.*).

Upon reviewing Tanaka, we find that Figure 6A does show the first portions in combination with the second portions defining the openings 130 where multiple rows of interconnect vias include at least two spaced apart rows. We also note that the spaced apart rows of vias are not claimed to be confined within each first portion, and only are required to be related to and arranged "for each of the first portions," as recited in claim 17. Although some portions appear to have more than two rows, the vias are arranged in at least two rows that, although by a small distance, are indeed spaced from each other.

Similarly, with respect to claim 18, Appellants argue that since no portions in Tanaka are shown to include at least two rows of vias, the portions are not enlarged enough to accommodate two rows (App. Br. 16;

Reply Br. 13-14). We again disagree and find that the portions shown in Figure 6A of Tanaka have enlarged widths compared to those in Figure 2A in order to accommodate the rows of interconnect vias.

In view of the above discussions, we find that the Examiner has properly relied on the disclosure of Suzuki and Tanaka to render obvious the subject matter of claims 17 and 18. Therefore, to the extent claimed, the combination of Suzuki and Tanaka suggests the subject matter recited in claims 17 and 18.

35 U.S.C. § 103 Rejection of Claims 2 and 21

With respect to claim 2, Appellants argue the patentability of the claim based on the same contentions presented with respect to claim 1 (App. Br. 17; Reply Br. 15), which are discussed above and found to be unpersuasive. However, with respect to claim 21, Appellants argue that the AAPA Figure 2 does not show an active circuit including an input/output bus and metal layers, at least partially, under the active circuit (App. Br. 17-18; Reply Br. 15-16). We agree with the Examiner (Ans. 12) that the AAPA Figures 1 and 2 show that a plurality of metal layers are, at least partially, under the active circuit and around a periphery. Although the Examiner's position is stated with minimal details, it is implied that the claim limitation of "under" has been interpreted as "at a lower level" by the Examiner. We find such interpretation to be reasonable as the claim does not require the metal layers to be directly below or under the active area.

In view of the above discussions, we find that the Examiner has properly relied on the disclosure of Suzuki and Tanaka in combination with AAPA to render obvious the subject matter of claims 2 and 21. Therefore,

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Application 10/633,004

to the extent claimed, we find that the combination of Suzuki and Tanaka with AAPA suggests the subject matter recited in claims 2 and 21.

DECISION

The decision of the Examiner with respect to the 35 U.S.C. § 103 rejections of the claims is affirmed, but is reversed with respect to their rejection under 35 U.S.C. § 112.

No time period for taking any subsequent action in connection with this appeal may be extended under 37 CFR § 1.136(a)(1)(iv).

Appeal 2007-4511
Application 10/633,004

AFFIRMED

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APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.
10/633,004	07/31/2003	Inderjit Singh	NVIDP234/P000825	8949
28875	7590	04/10/2008	EXAMINER	
Zilka-Kotab, PC P.O. BOX 721120 SAN JOSE, CA 95172-1120			VU, HUNG K	
			ART UNIT	PAPER NUMBER
			2811	
			MAIL DATE	DELIVERY MODE
			04/10/2008	PAPER

Please find below and/or attached an Office communication concerning this application or proceeding.

The time period for reply, if any, is set in the attached communication.

Notice of Abandonment

Application No.

10/633,004

Examiner

HUNG VU

Applicant(s)

SINGH ET AL.

Art Unit

2811

-- The MAILING DATE of this communication appears on the cover sheet with the correspondence address--

This application is abandoned in view of:

1. ☐ Applicant's failure to timely file a proper reply to the Office letter mailed on _____.
 - (a) ☐ A reply was received on _____ (with a Certificate of Mailing or Transmission dated _____), which is after the expiration of the period for reply (including a total extension of time of _____ month(s)) which expired on _____.
 - (b) ☐ A proposed reply was received on _____, but it does not constitute a proper reply under 37 CFR 1.113 (a) to the final rejection.
(A proper reply under 37 CFR 1.113 to a final rejection consists only of: (1) a timely filed amendment which places the application in condition for allowance; (2) a timely filed Notice of Appeal (with appeal fee); or (3) a timely filed Request for Continued Examination (RCE) in compliance with 37 CFR 1.114).
 - (c) ☐ A reply was received on _____ but it does not constitute a proper reply, or a bona fide attempt at a proper reply, to the non-final rejection. See 37 CFR 1.85(a) and 1.111. (See explanation in box 7 below).
 - (d) ☐ No reply has been received.
2. ☐ Applicant's failure to timely pay the required issue fee and publication fee, if applicable, within the statutory period of three months from the mailing date of the Notice of Allowance (PTOL-85).
 - (a) ☐ The issue fee and publication fee, if applicable, was received on _____ (with a Certificate of Mailing or Transmission dated _____), which is after the expiration of the statutory period for payment of the issue fee (and publication fee) set in the Notice of Allowance (PTOL-85).
 - (b) ☐ The submitted fee of \$_____ is insufficient. A balance of \$_____ is due.
The issue fee required by 37 CFR 1.18 is \$_____. The publication fee, if required by 37 CFR 1.18(d), is \$_____.
 - (c) ☐ The issue fee and publication fee, if applicable, has not been received.
3. ☐ Applicant's failure to timely file corrected drawings as required by, and within the three-month period set in, the Notice of Allowability (PTO-37).
 - (a) ☐ Proposed corrected drawings were received on _____ (with a Certificate of Mailing or Transmission dated _____), which is after the expiration of the period for reply.
 - (b) ☐ No corrected drawings have been received.
4. ☐ The letter of express abandonment which is signed by the attorney or agent of record, the assignee of the entire interest, or all of the applicants.
5. ☐ The letter of express abandonment which is signed by an attorney or agent (acting in a representative capacity under 37 CFR 1.34(a)) upon the filing of a continuing application.
6. ☒ The decision by the Board of Patent Appeals and Interference rendered on 03/27/08 and because the period for seeking court review of the decision has expired and there are no allowed claims.
7. ☐ The reason(s) below:

/Hung Vu/
Primary Examiner, Art Unit 2811

Petitions to revive under 37 CFR 1.137(a) or (b), or requests to withdraw the holding of abandonment under 37 CFR 1.181, should be promptly filed to minimize any negative effects on patent term.